



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/757,276
Filing Date January 14, 2004
Inventor Kevin Beaman
Assignee Micron Technology, Inc.
Group Art Unit 2813
Examiner Stephen Smoot
Attorney's Docket No. MI22-2475
Customer No. 021567
Title: Semiconductor Assemblies, Methods of Forming Structures over Semiconductor
Substrates, and Methods of Forming Transistors Associated with Semiconductor
Substrates

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


Reference - - See attached Form PTO-1449

The attached Form PTO-1449 is submitted In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the references listed on the attached Form PTO-1449. Pursuant to Federal Register Vol. 69, No. 182, pg. 56542 (September 21, 2004), no copies of any cited U.S. patents or U.S. published applications are included herewith. Copies of all other cited art references, if any, are attached. No admission is made regarding whether the submitted references are prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date: 11-21-06


D. Brent Kenady
Reg. No. 40,045
Customer No. 021567

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
MI22-2475SERIAL NO.
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U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
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	AB						
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FOREIGN PATENT DOCUMENTS

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